

Investigation of PMT aging in Novosibirsk

*A.Yu.Barnyakov, M.Yu.Barnyakov, V.S.Bobrovnikov, A.R.Buzykaev, S.A.Kononov,
E.A.Kravcheko, A.P.Onuchin*

Budker Institute of Nuclear Physics, Novosibirsk, Russia

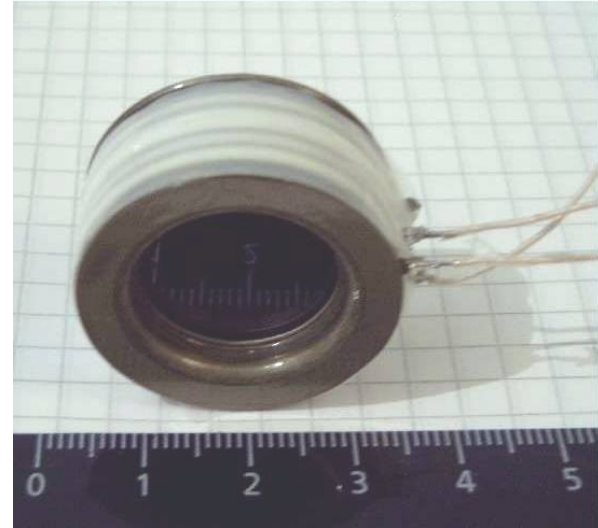
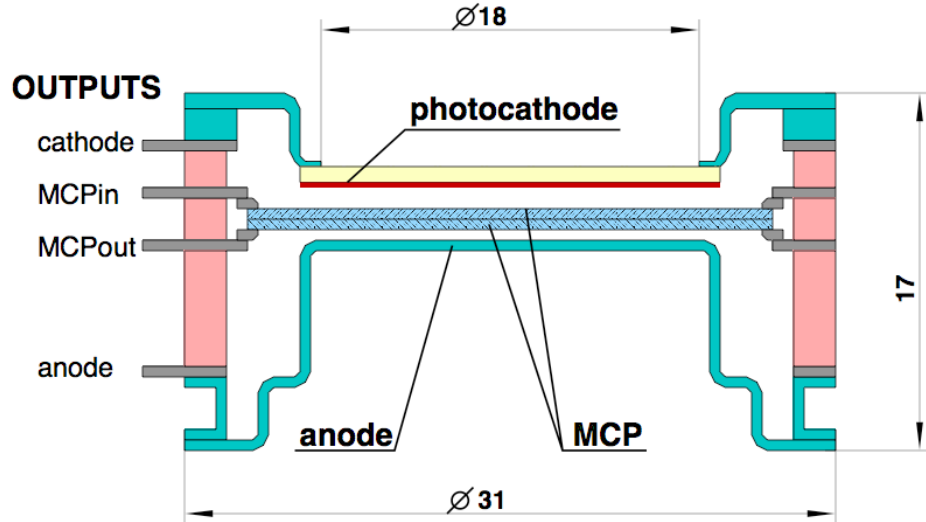
A.V.Mironov

Ekran FEP, Novosibirsk, Russia

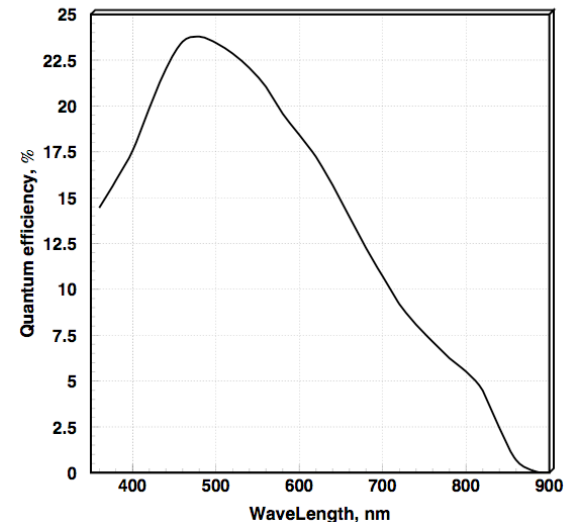
Outline:

- Use of MCP PMTs in BINP detectors
- Experimental setup
- QE degradation versus wavelength
- QE degradation at different countin rates
- Example of aging test results
- Questions and suggestions to H8500 aging tests

MCP PMT under investigation



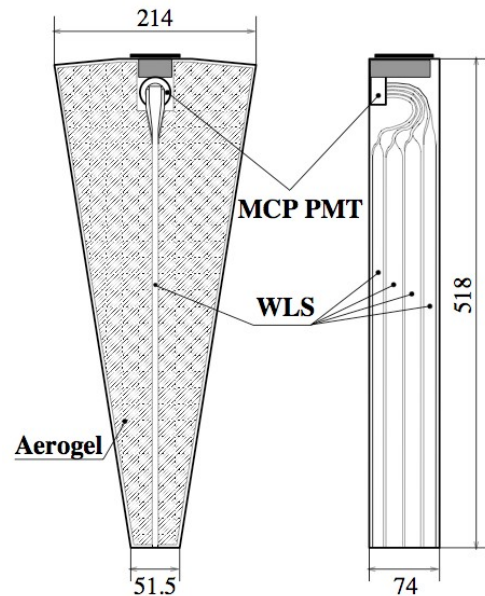
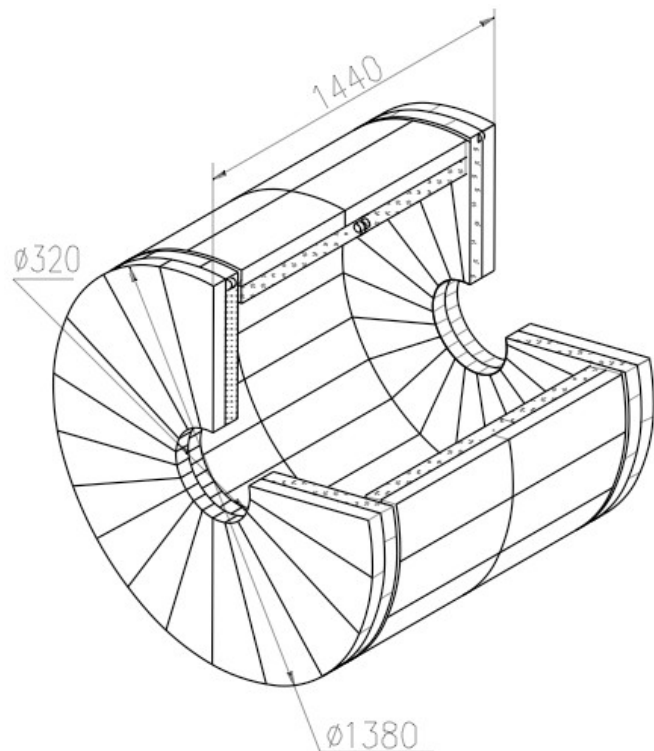
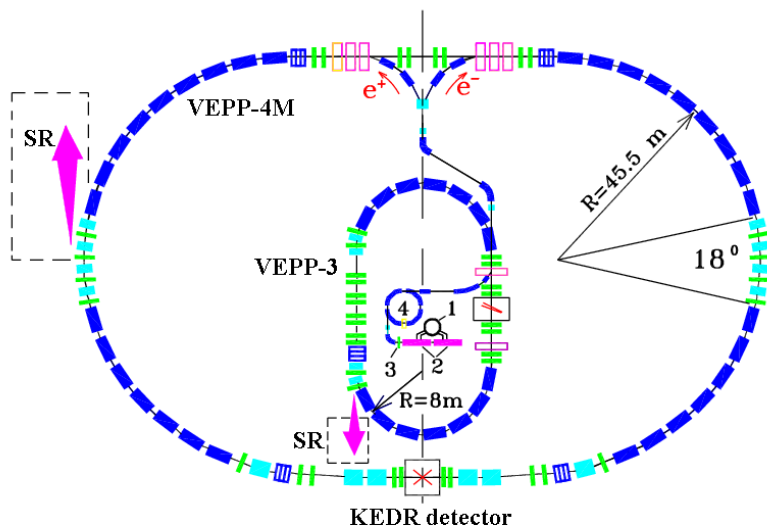
Manufacturer: "Ekran FEP" (Novosibirsk)
Borosilicate glass window
Multialkali (Sb-Na-K-Cs) photocathode
Maximum QE at $\lambda=500\text{nm}$
Two MCPs with channel diameter of $7\text{ }\mu\text{m}$
Channel bias angle 13°
Single anode



13.09.2011

ASHIPH counters for KEDR

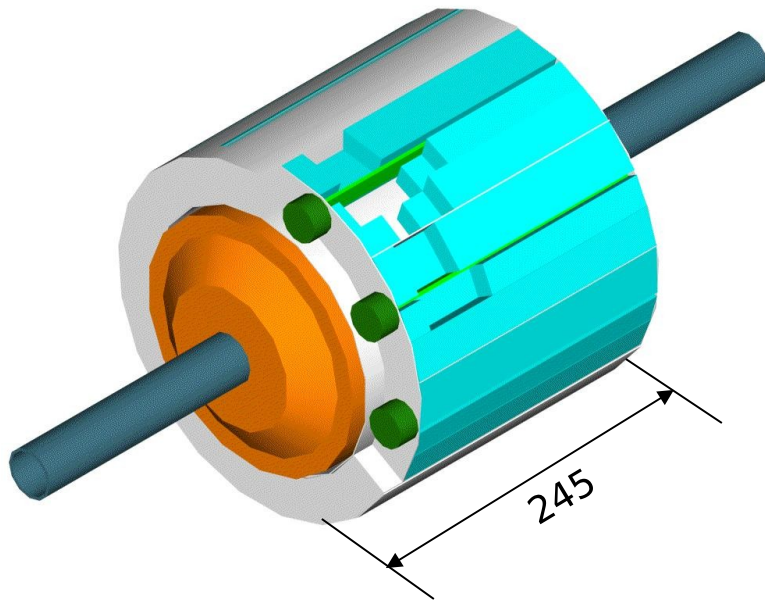
- π/K separation in momenta range $0.6 \div 1.5 \text{ GeV/c}$
- Aerogel $n=1.05$ (1000 litres)
- 160 MCP PMT
- Magnetic field up to 1.5 T



80 counters have been working since 2003

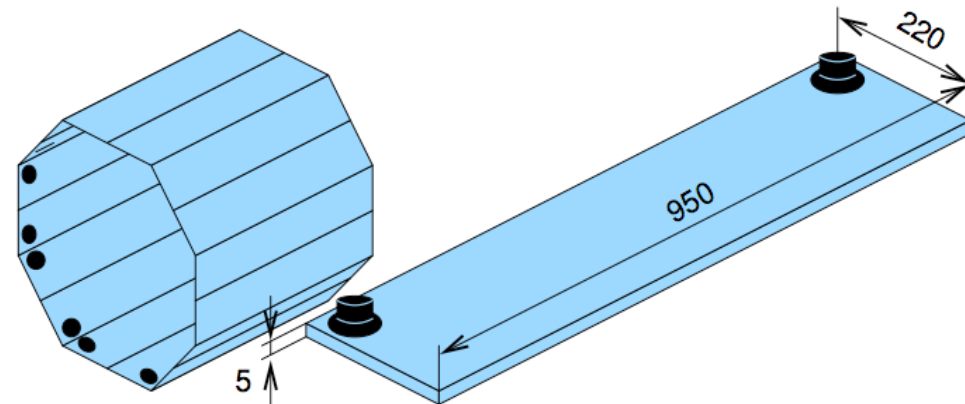
ASHIPH counters for SND

- π/K separation in momenta range
300 ÷ 870 MeV/c
- Aerogel $n=1.13$
- 9 MCP PMT
- No magnetic field



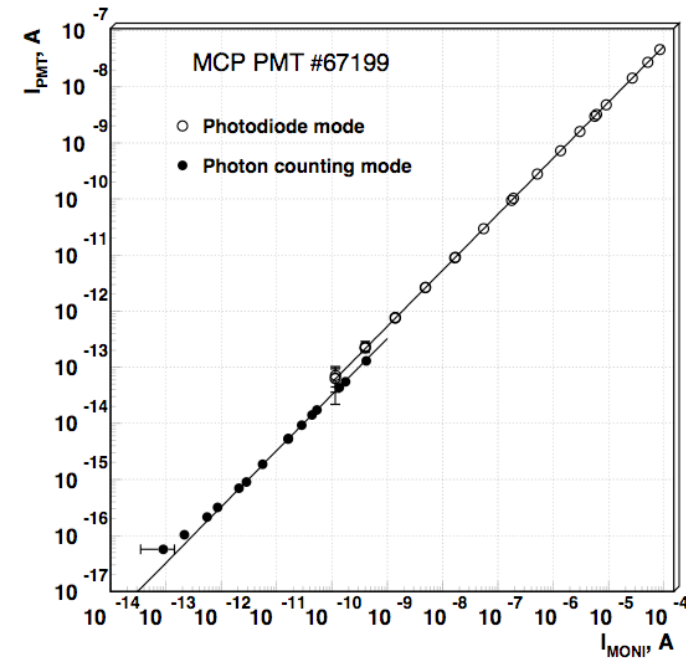
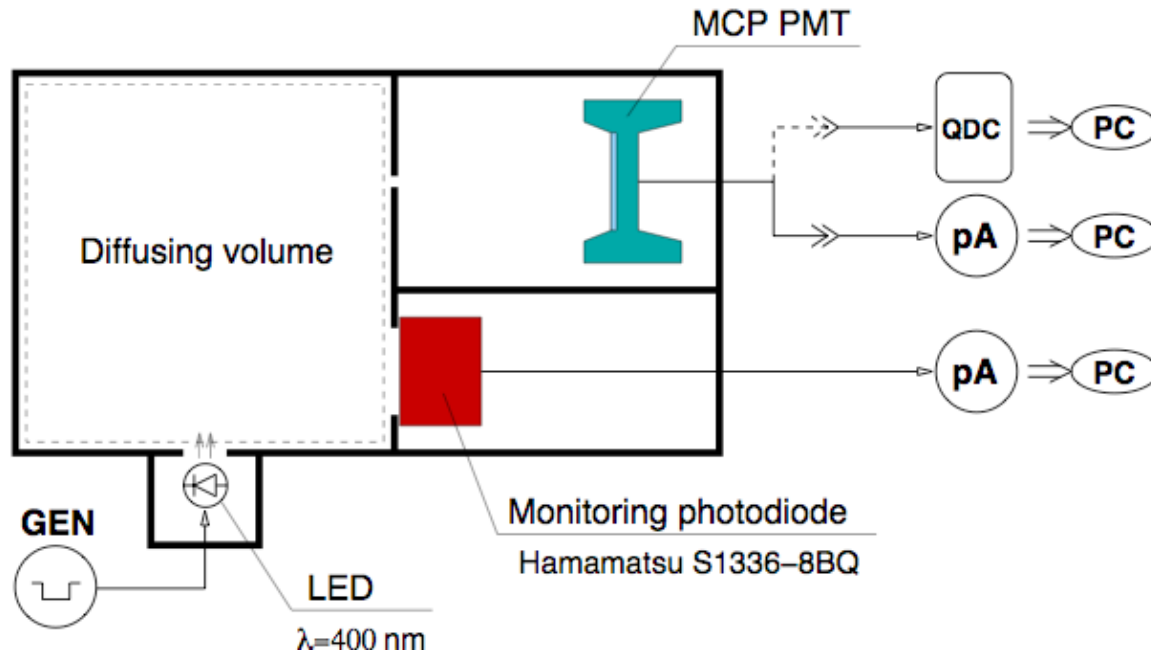
TOF counters for CMD-3

- Antineutron identification
- BC-408 scintillator (16 bars)
- 32 MCP PMT



SND and CMD-3 are working at VEPP-2000 e^+e^- collider in BINP

Setup for MCP PMT aging study



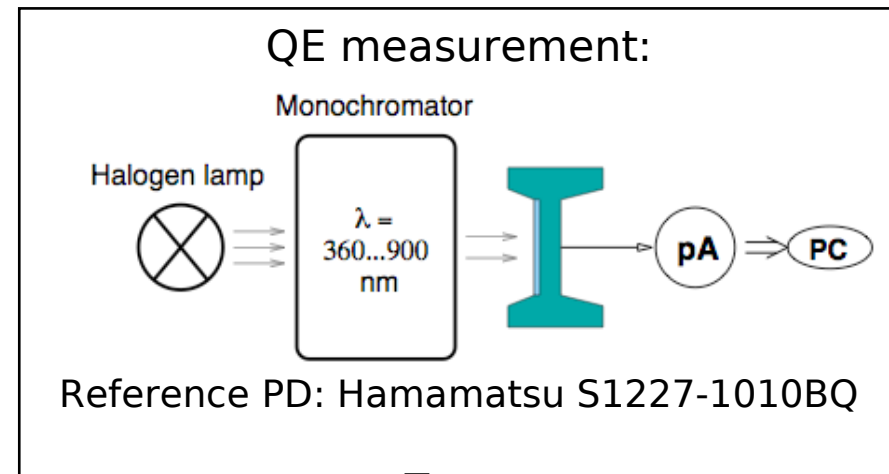
Low light intensity (photon counting mode):

$$K = R_{\text{PMT}} / I_{\text{MONI}}$$

High light intensity (direct current mode):

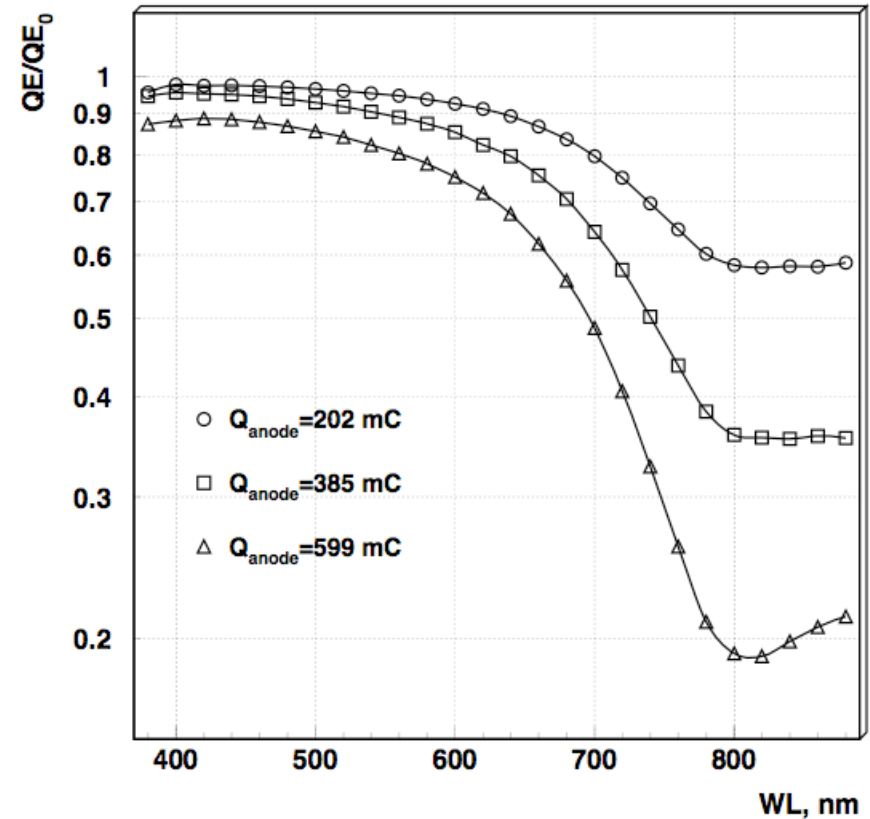
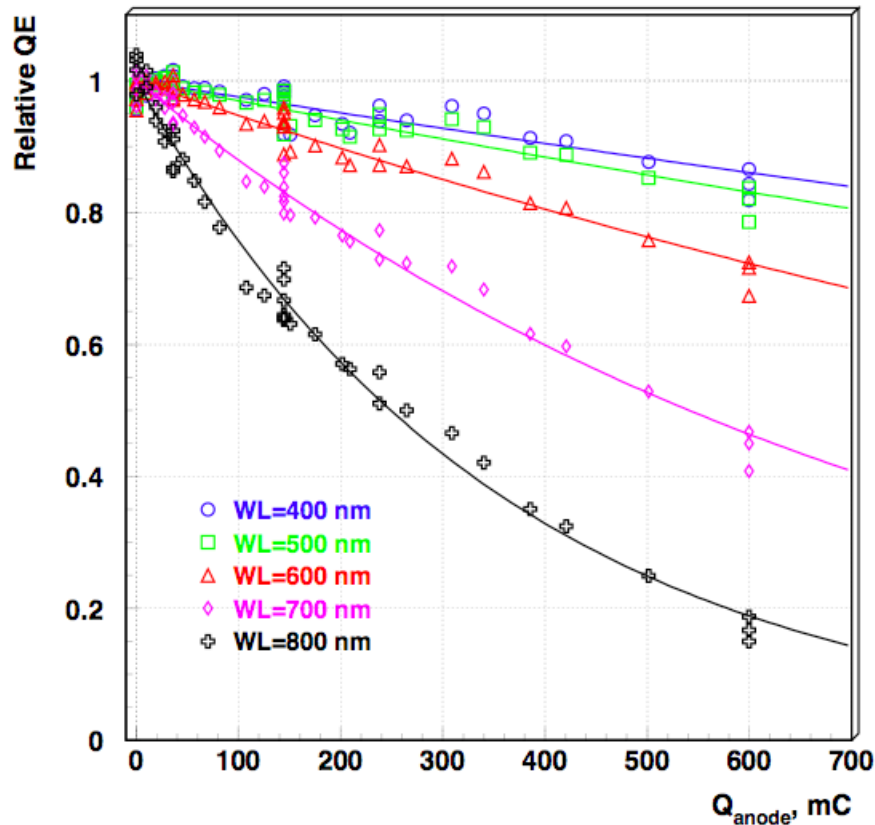
$$R_{\text{PMT}} = I_{\text{MONI}} K$$

13.09.2011



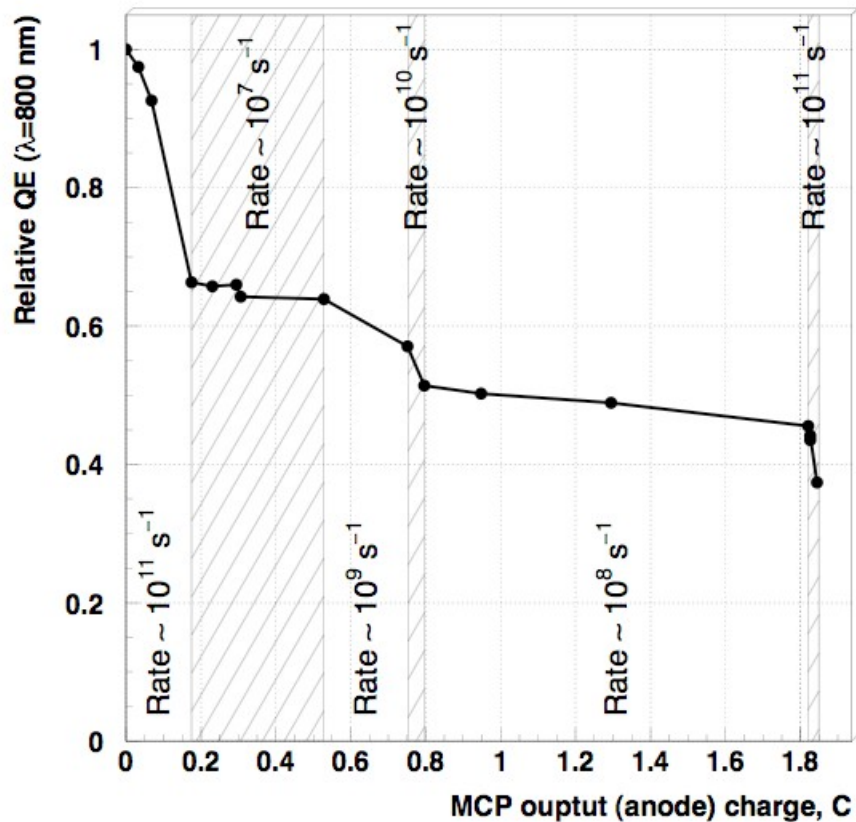
QE degradation versus wavelength

MCP PMT #2071 (two MCPs)

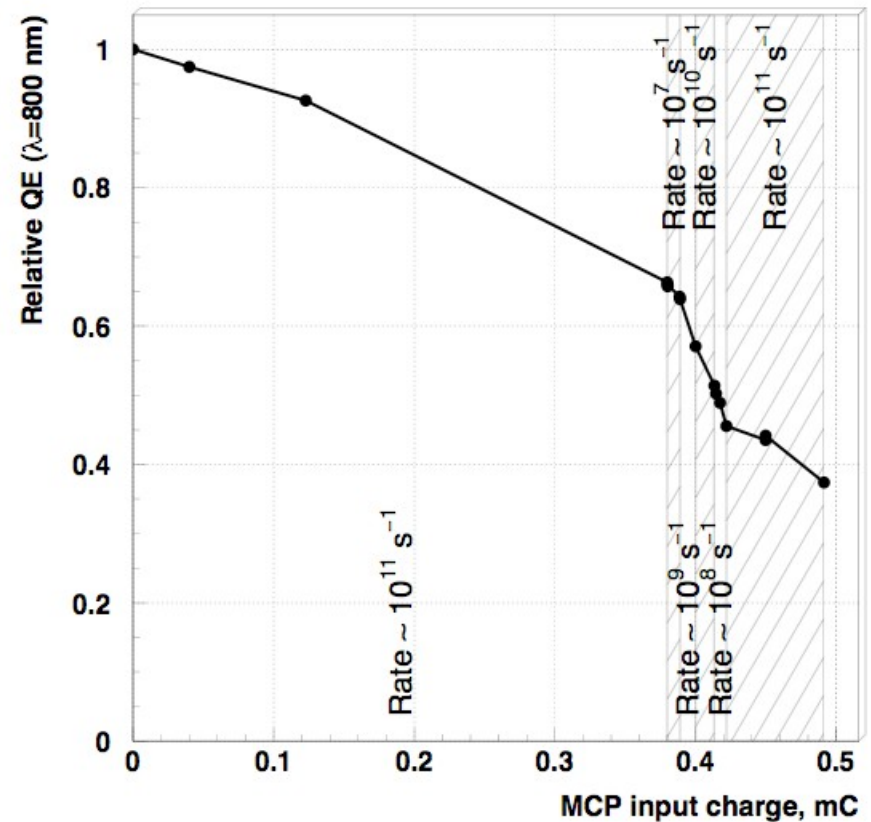


Possibility to control photocathode aging after short exposure not damaging QE in the 'working' region

QE degradation at different counting rates

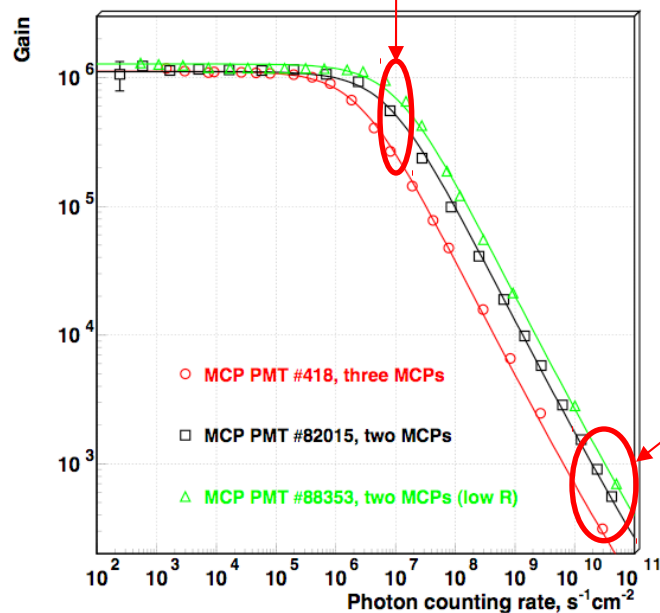
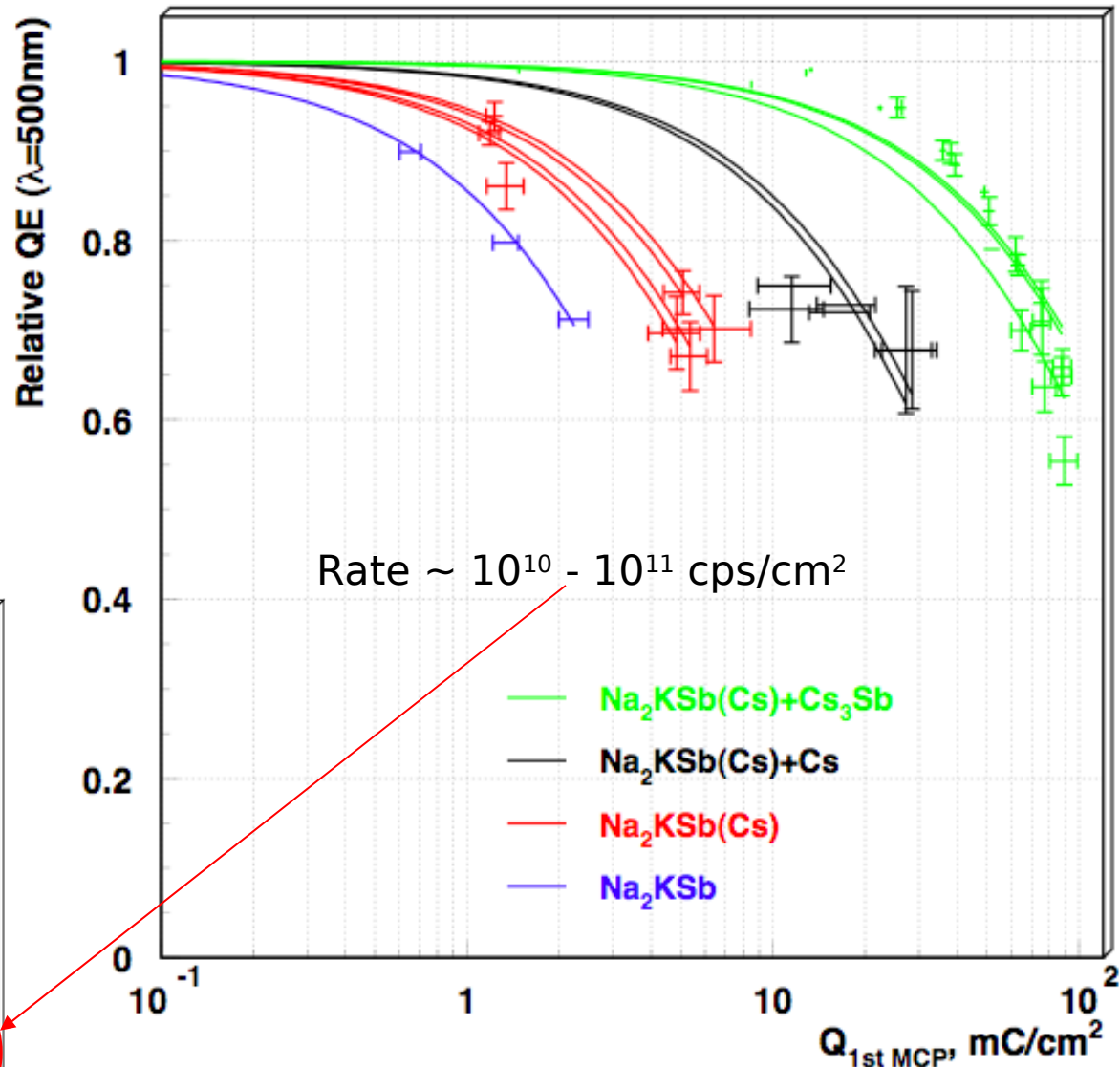
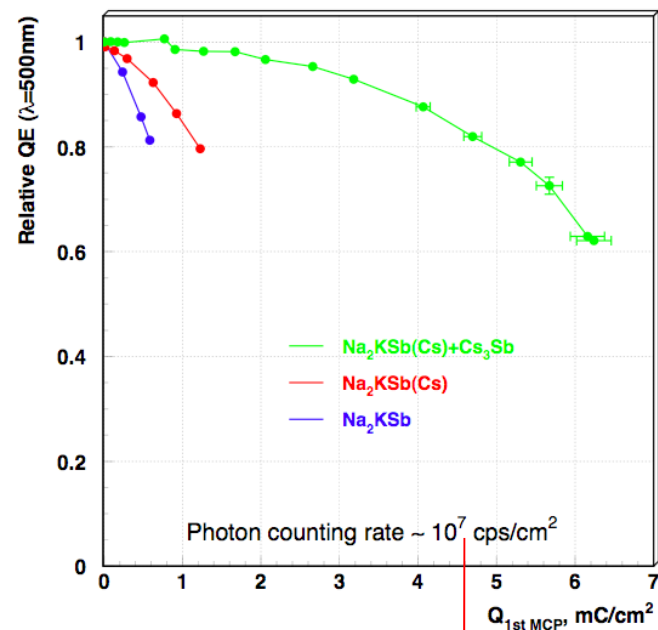


The higher counting rate the faster QE degradation per unit of anode charge



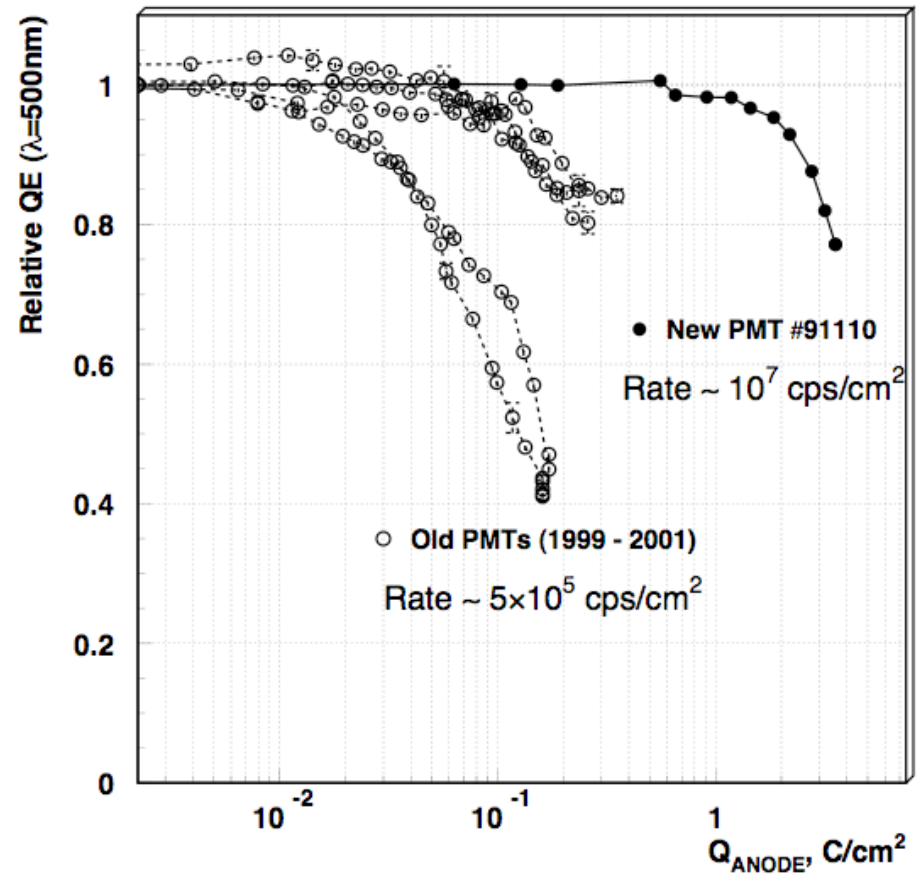
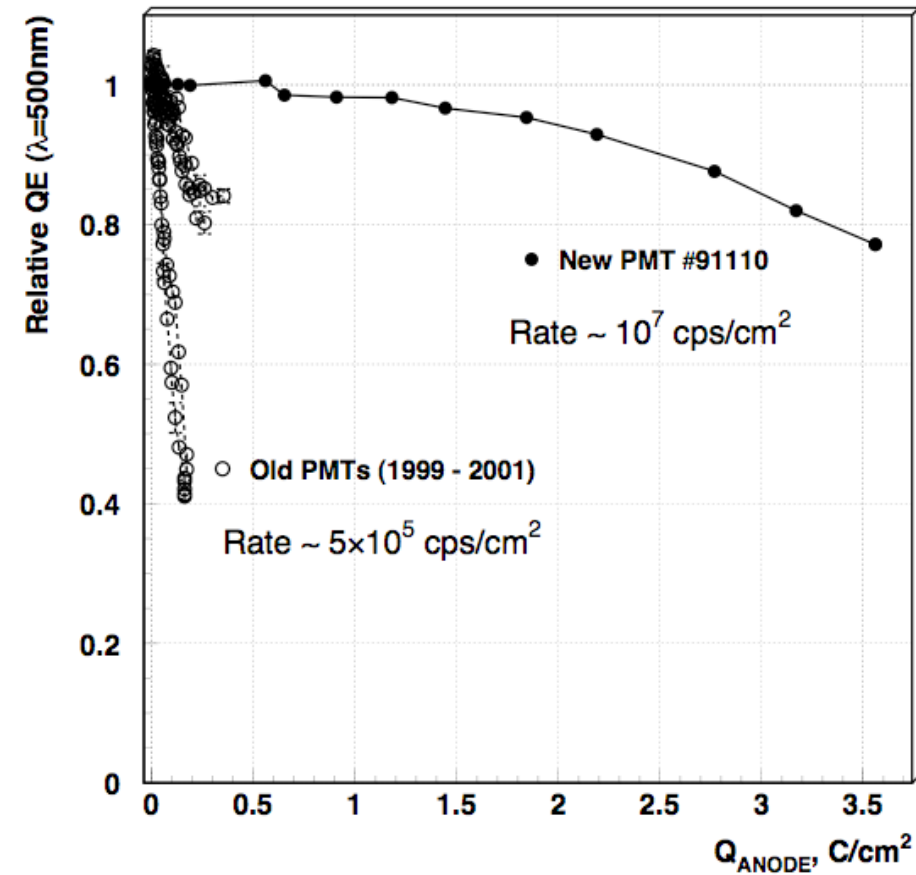
The higher counting rate the slower QE degradation per unit of cathode charge

Photocathodes: aging comparison at different rates



DIP11, Lyon, 06.07.18

Best sample: comparison with old tubes



Lifetime improved by one order of magnitude (at least)!

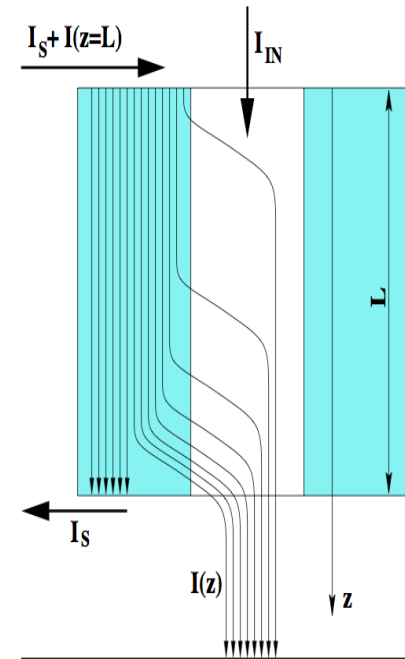
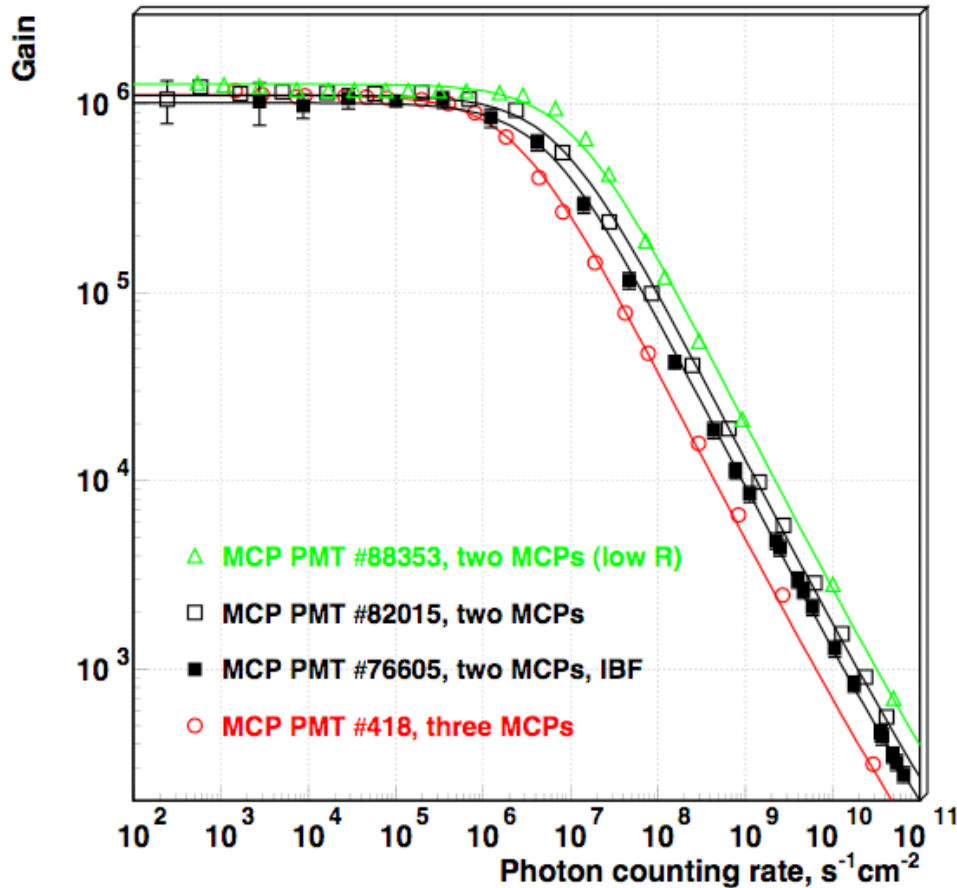
Suggestions for Hamamatsu H8500 aging tests:

- Preliminary tests:
 - Local illumination $\sim 10 \div 15$ mm diameter
 - Series of “short” tests with increasing intensity
 - QE measurement with monochromator in photodiode mode (is it possible?)
- Main tests:
 - Full photocathode illumination
 - Nominal voltage
 - Highest possible rate to have result after 3-6 months of continuous illumination
- Questions:
 - Anticipated photon flux in DIRC at SuperB?
 - Working amplification of PMT?
 - Is it possible to work in photodiode mode (to connect directly to the 1-st dynode)?
 - Who has an extra H8500 for aging tests?

Additional slides

Gain decrease at high counting rate

A.B.Berkin and V.V.Vasilyev,
Technical Physics, 2008, Vol. 53, No. 2,
p.272



$$I(z) = I_{in} e^{\alpha z} \ln(G_0) / F / (1 + I_{in}/I_s \cdot e^{\alpha z})$$

where

$$F = \ln(G_0) + \ln(1 + I_{in}/I_s) - \ln(1 + I_{in}/I_s \cdot G_0)$$

$$\alpha = \ln(G_0)/L$$

$$G = G_0 \cdot \ln(G_0) / F / (1 + I_{in}/I_s \cdot e^{\alpha z})$$

13.09.2011

12

Calculation of 1st MCP current

Approximation of
dependence $I_{\text{OUTPUT}} (I_{\text{INPUT}})$:

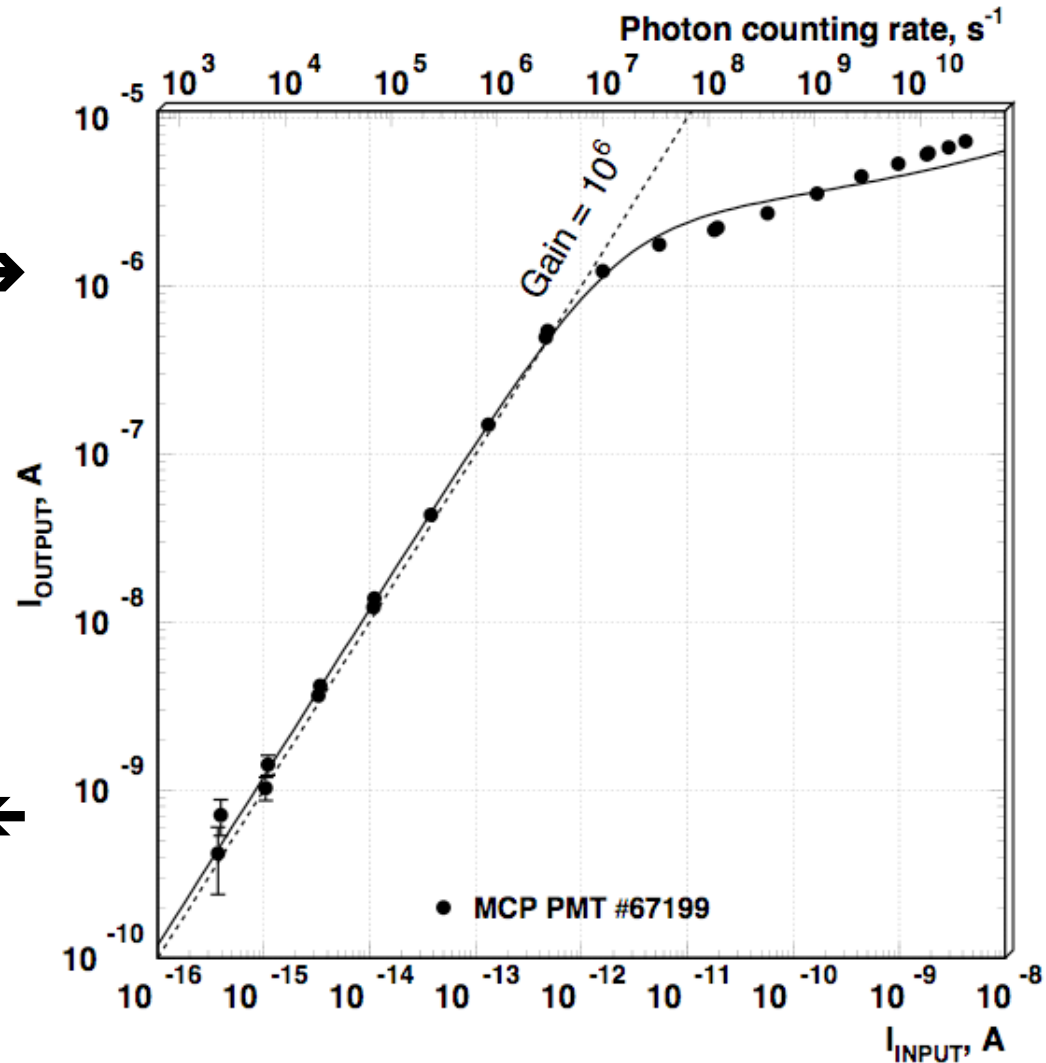
$$I(z=L) = f(I_{\text{in}}, G_0, I_s)$$

G_0 and I_s - free parameters

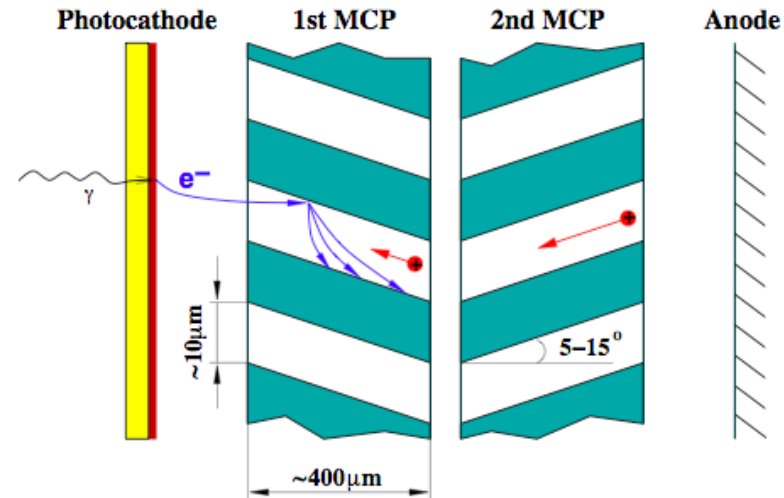
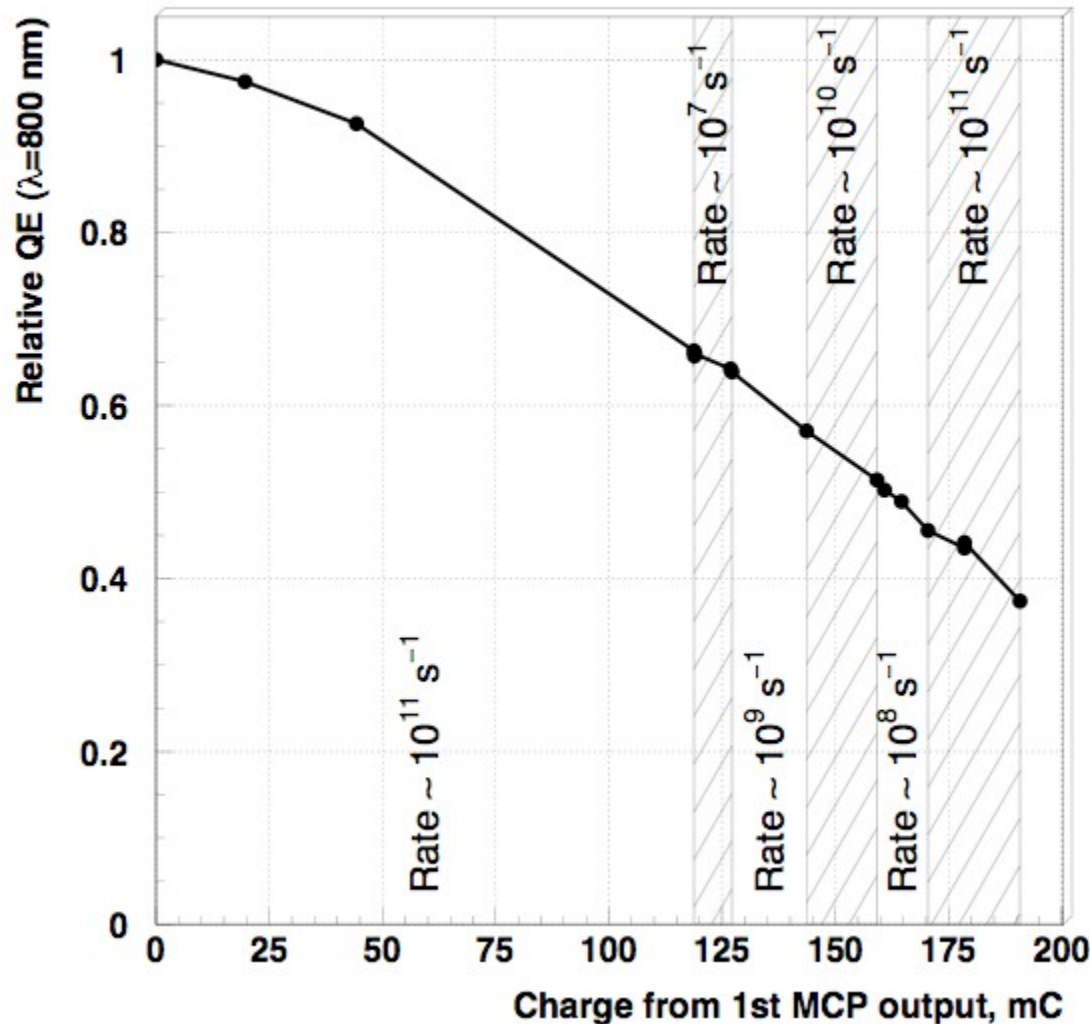


Calculation of the current
extracted from 1st MCP :

$I(z=L/2)$ using G_0 and I_s
obtained from approximation



QE degradation vs. charge from 1st MCP



Correlation between QE degradation rate and photon counting rate is not observed !

Use of the result:

- Correct comparison of the aging of different samples of PMT.
- Lifetime improvement by redistribution of gain between 1st and 2nd MCP.

Enhancement of MCP degassing: gain

Two stage of MCP degassing:

1. Heating

2. Electron scrubbing

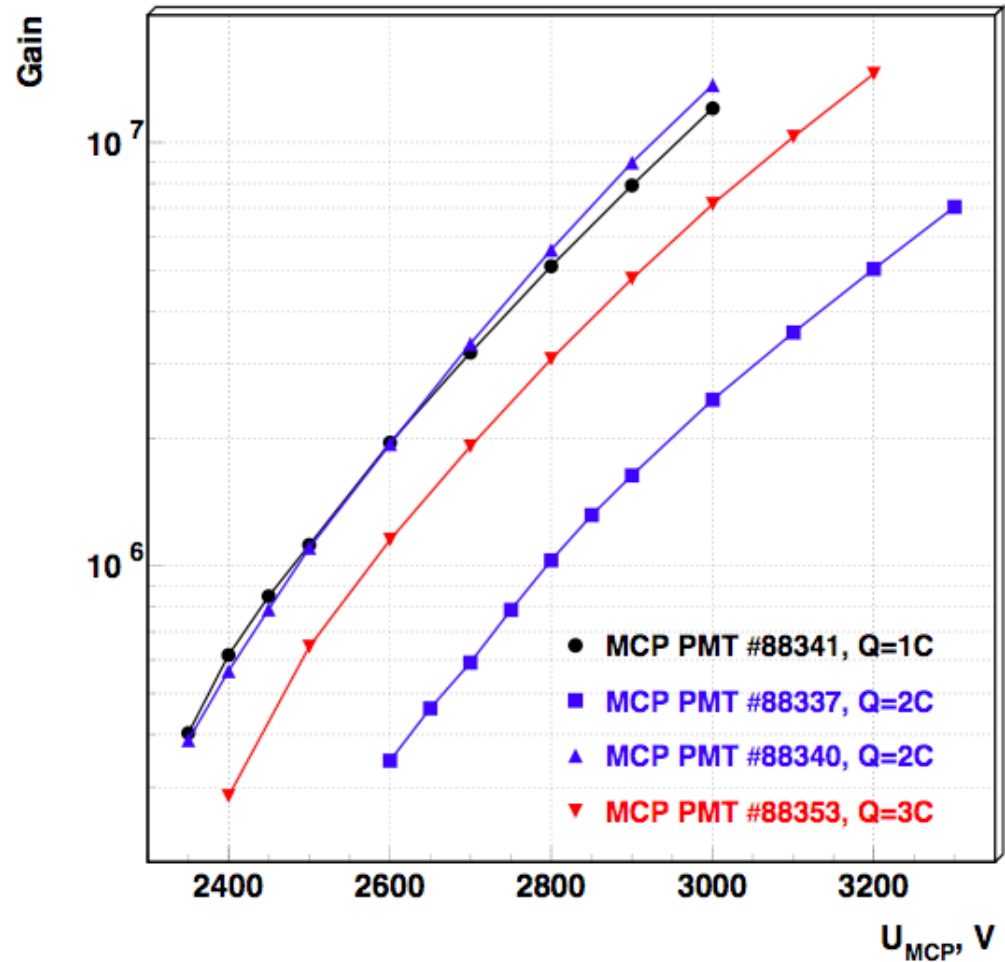
+ Photocathode lifetime increase

- Gain degradation

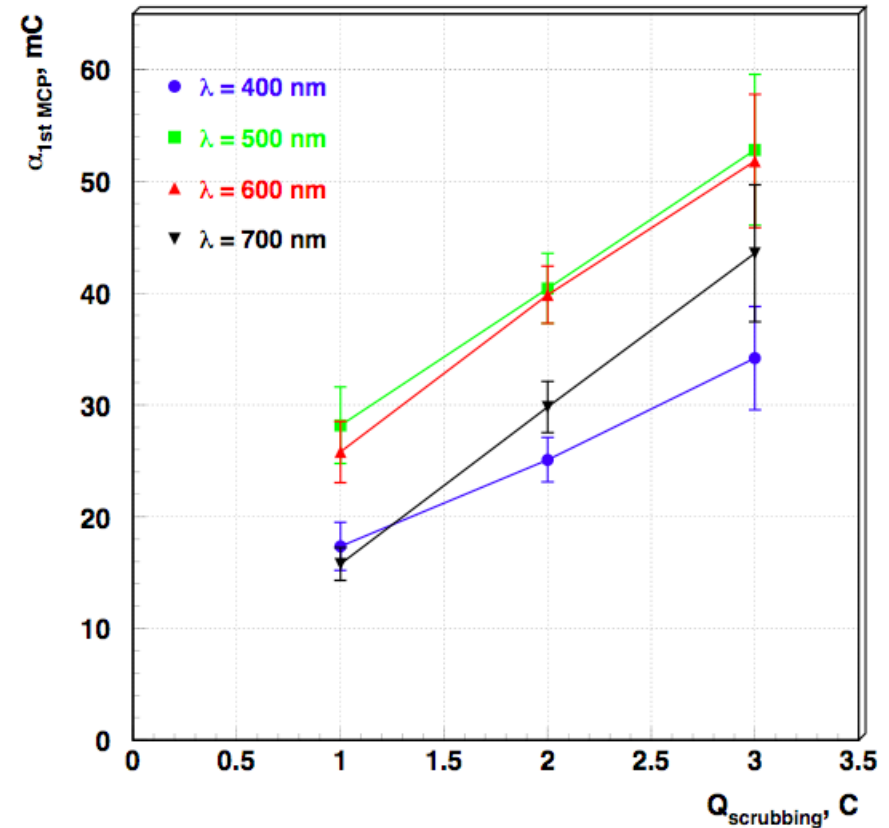
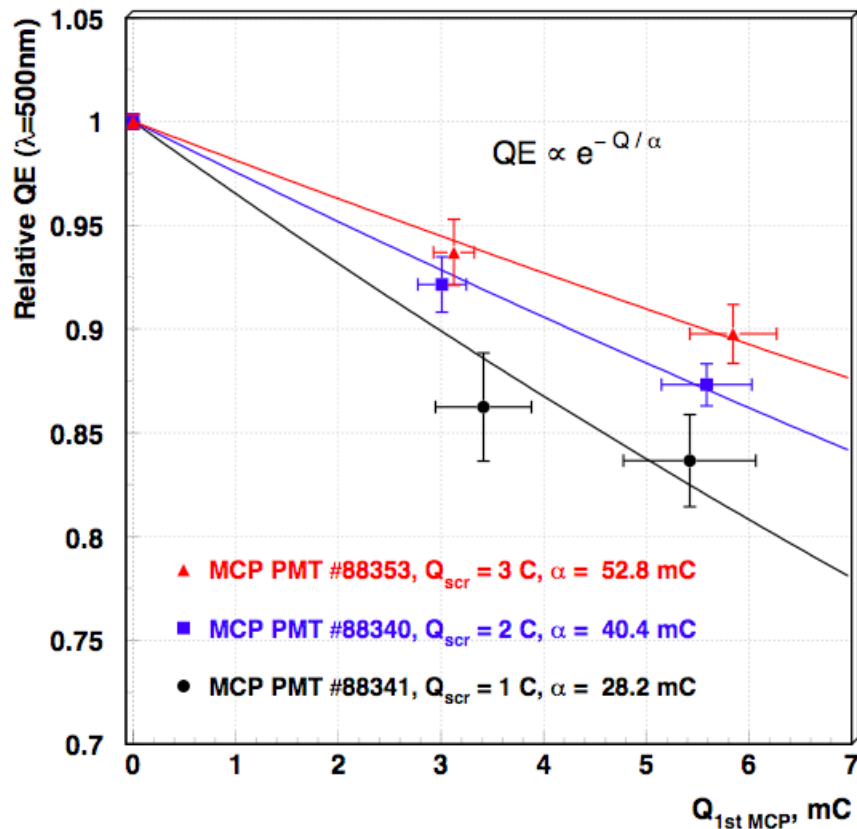
Duration of electron scrubbing
has been increased in 2 and 3
times



MCP gain is not affected
(large spread of initial MCP
quality)



Enhancement of MCP degassing: aging

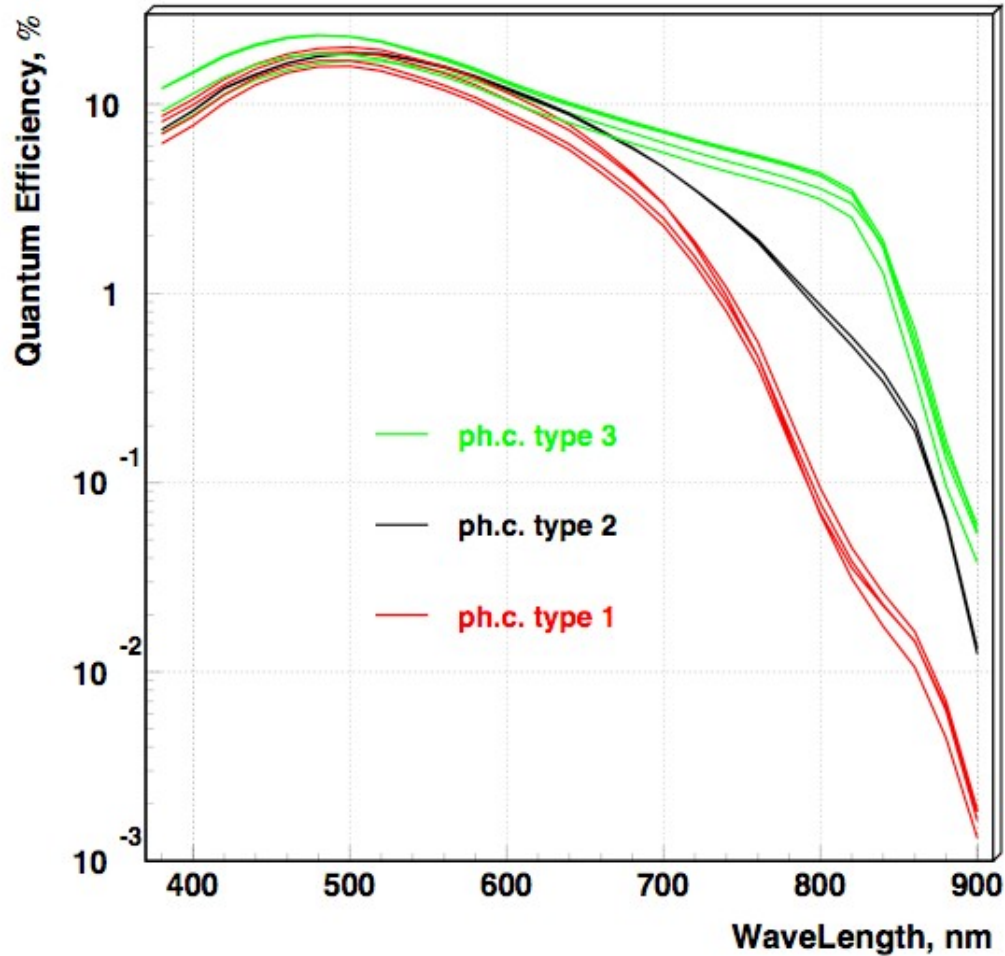


Three times better electron scrubbing



Two times slower QE degradation

Photocathodes: spectral response



Type 1: $\text{Na}_2\text{KSb}(\text{Cs})$

Dark rate ~ 0.5 kcps/cm²

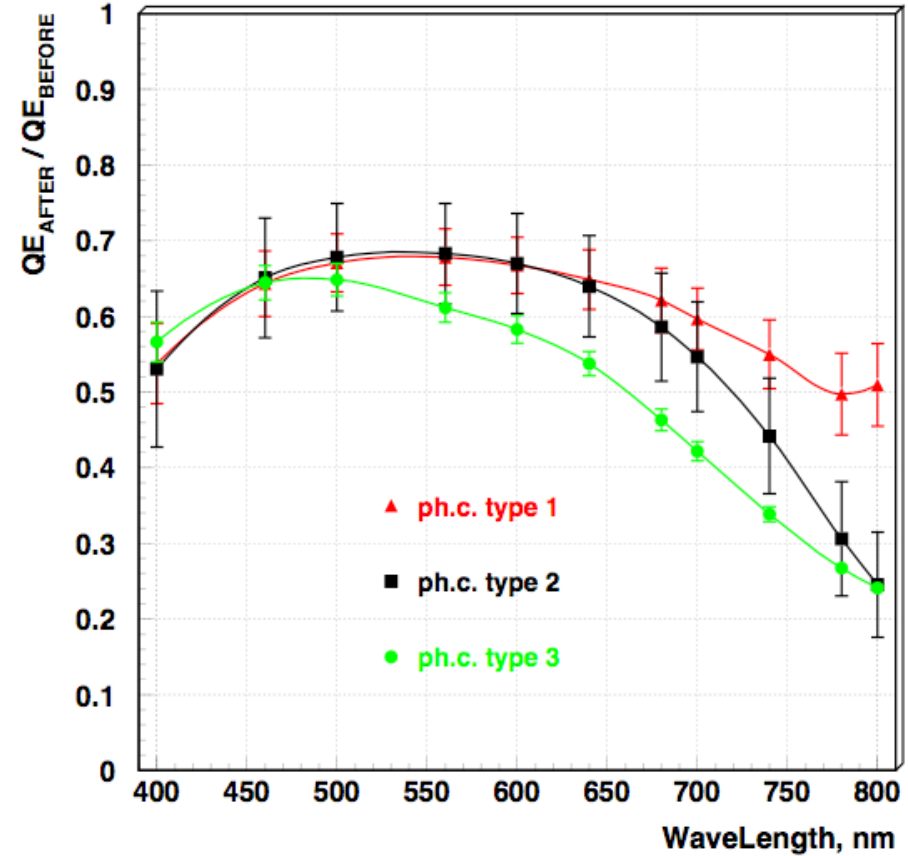
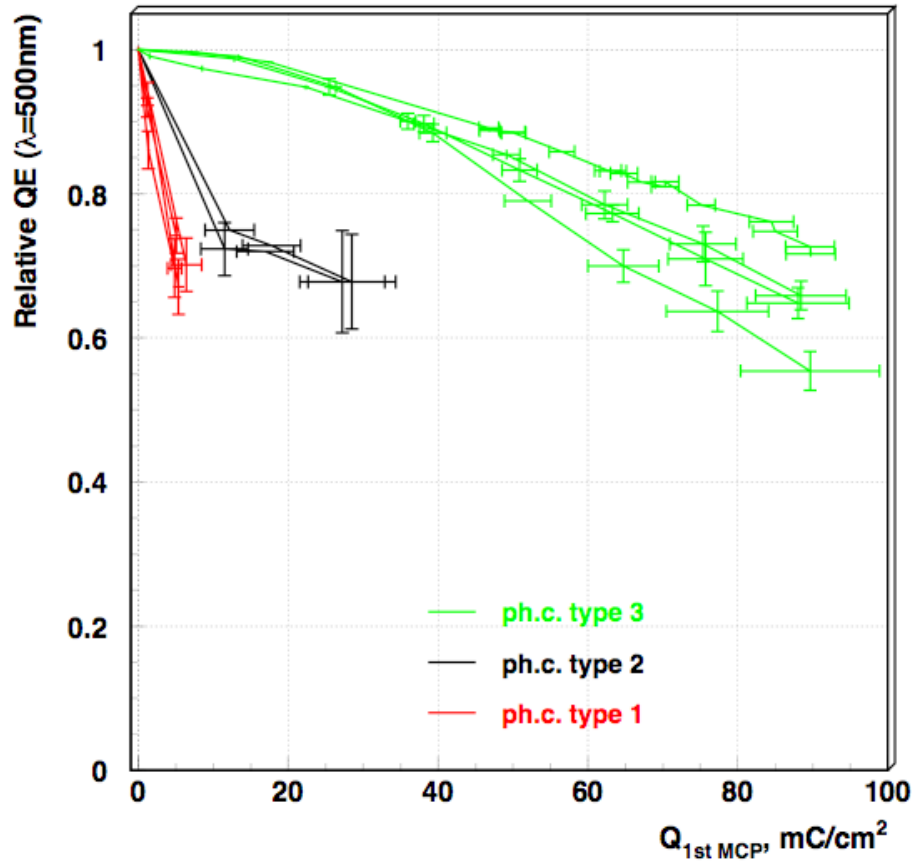
Type 2: $\text{Na}_2\text{KSb}(\text{Cs}) + \text{Cs}$

Dark rate ~ 5 kcps/cm²

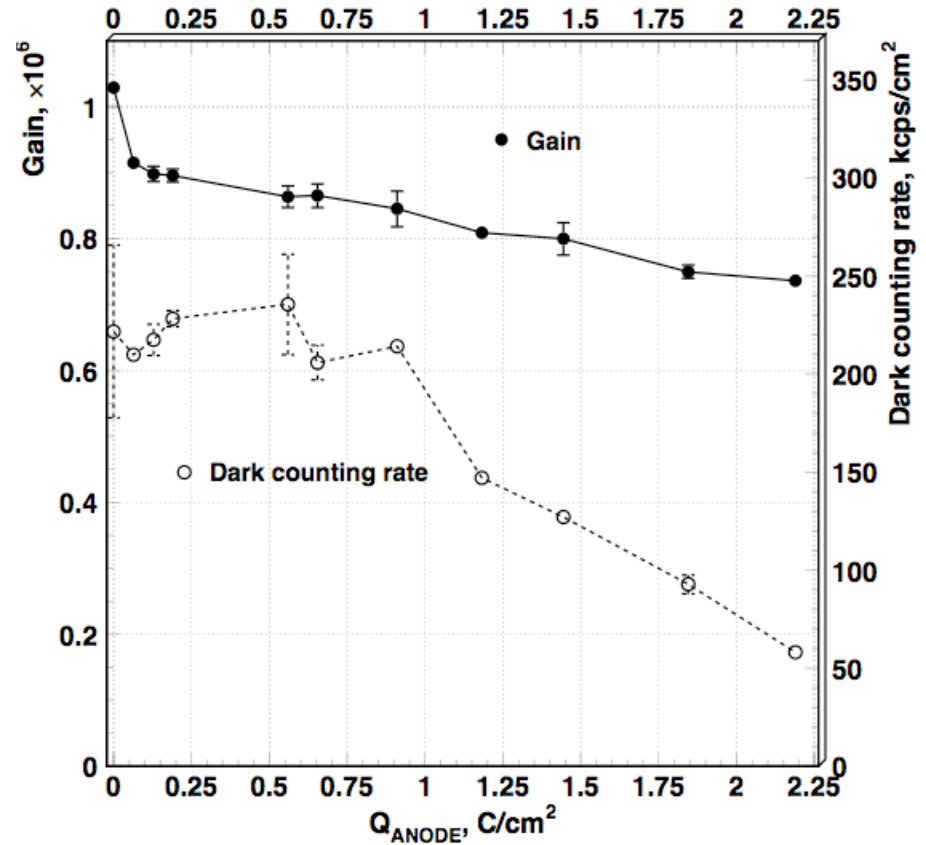
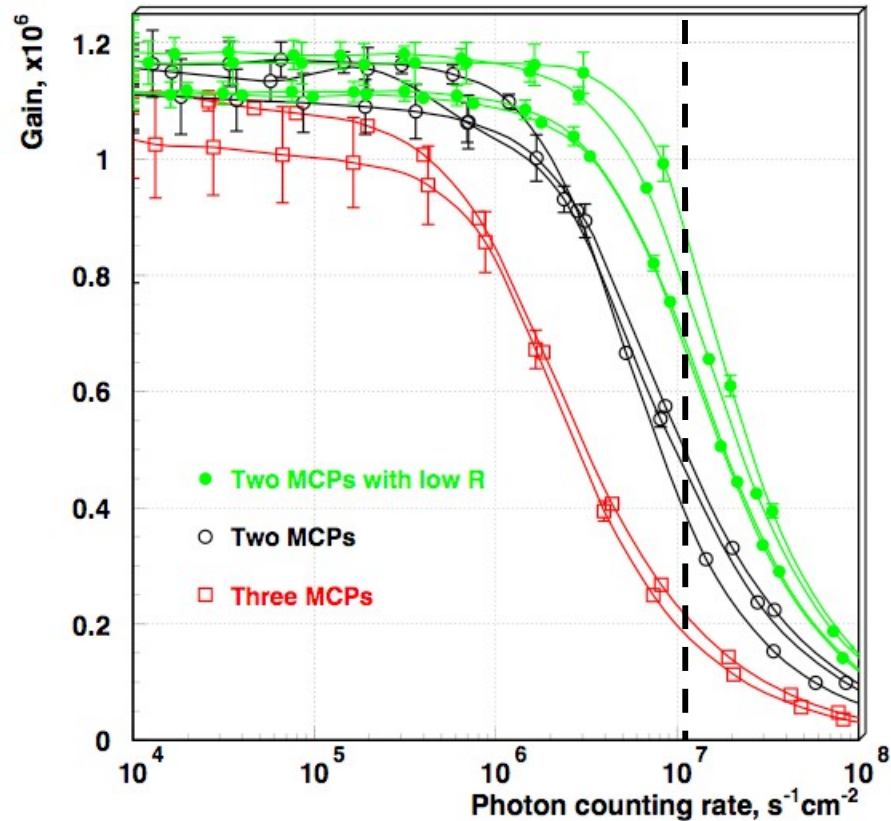
Type 3: $\text{Na}_2\text{KSb}(\text{Cs}) + \text{Cs}_3\text{Sb}$

Dark rate $\sim 50-100$ kcps/cm²

Photocathodes: aging comparison

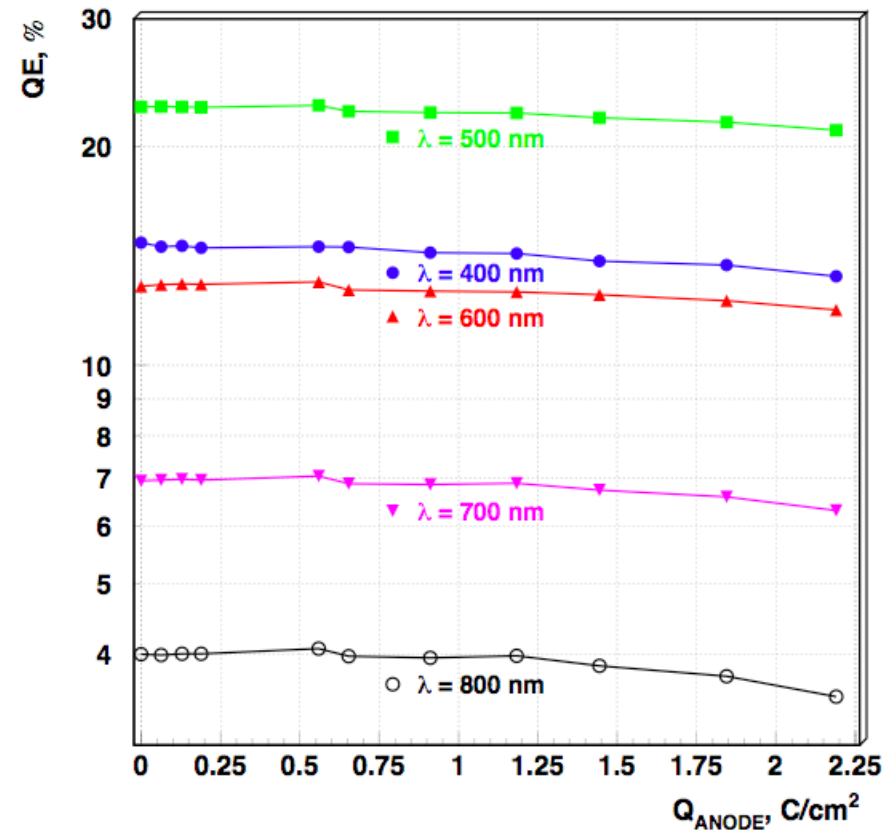
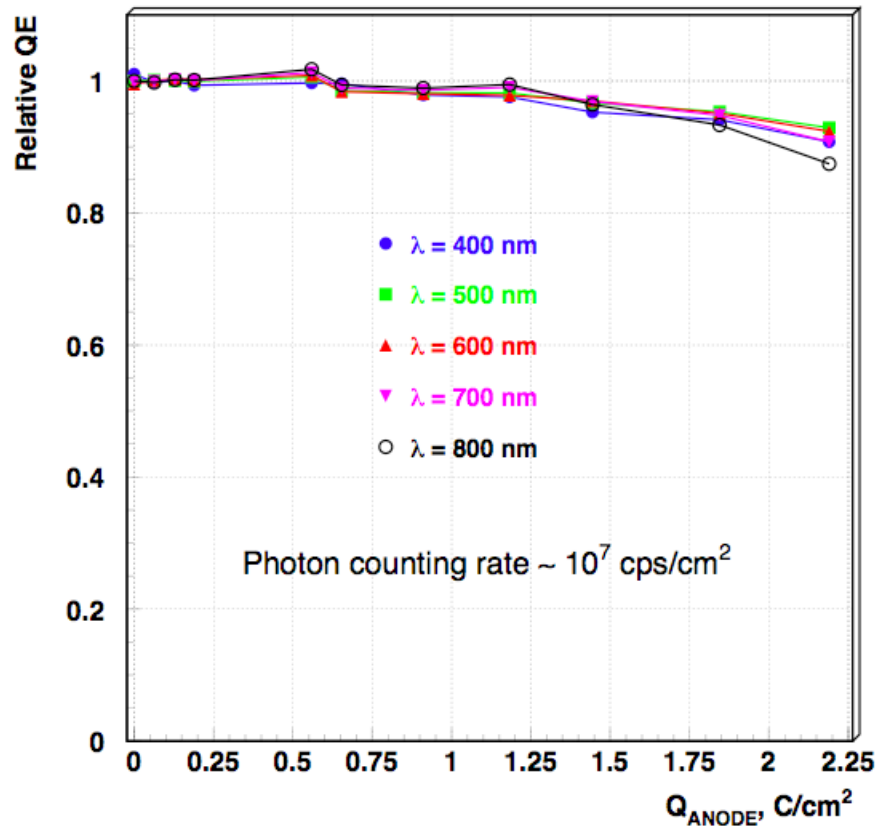


MCP PMT #91110: gain and dark rate



Lifetime measurements at counting rate of $10^7 \text{ s}^{-1}\text{cm}^{-2}$
where gain decreases by 20-30%

MCP PMT #91110: photocathode lifetime



2 C/cm^2 of accumulated anode charge



7% degradation of QE